

PATENT APPLICATION

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Jeong-Hoon AHN, et al.
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Ex. Allan Wilson

INFORMATION DISCLOSURE CITATION
FORM PTO-1449 (Modified)U.S. PATENT DOCUMENTS

Exam Init	Ref	Document Number	Issue Date	Name	Class	Sub Class
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FOREIGN PATENT DOCUMENTS

Exam Init	Ref	Document Number	Publication Date	Country	Name
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OTHER DOCUMENTS

Exam Init	Ref	Author, Title, Date, Pertinent Pages, Etc.)
<u>all</u>		Lin, et al. "Single Mask Metal-Metal-Insulator-Metal (MIM) Capacitor with Copper Damascene Metallization for Sub-0.18 μ m Mixed Mode Signal and System-on-a Chip (SoC) Applications" IEEE 2000, pp.111-113 *
<u>all</u>		M. Armacost, et al. "A High Reliability Metal Insulator Metal Capacitor for 0.18 μ m Copper Technology" IEEE 2000, IEDM, pp.157-160 *

Examiner:

O. Neill

Date Considered:

10/5/05

* No month cited.